Notice of References Cited Application/Control No. 10/515,205 Applicant(s)/Patent Under Reexamination MIYATA ET AL. Examiner PEGAH PARVINI 1793 Applicant(s)/Patent Under Reexamination MIYATA ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0157304	08-2003	Li et al.	428/195
*	В	US-2002/0004131	01-2002	Darsillo et al.	428/328
*	С	US-6,465,670	10-2002	Thise et al.	556/400
*	D	US-2002/0065334	05-2002	Markowitz et al.	521/99
*	Е	US-5,922,299	07-1999	Bruinsma et al.	423/335
*	F	US-2001/0005567	06-2001	Harada et al.	430/32
*	G	US-2002/0155053	10-2002	Nishiyama et al.	423/335
*	Ι	US-2003/0031615	02-2003	SATOU et al.	423/335
	-	US-			
	٦	US-			
	K	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν	WO 99/26881	06-1999	WIPO	Satou et al.	C01B 37/02
	0					
	Ρ					
	σ					
	R					
	S					
	۲					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	W	
	×	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.